



MICROCHIP

QUALIFICATION REPORT SUMMARY

PCN#: NTDO-15NWUK778

Date:

September 30, 2025

**Qualification of MTAI as an additional final test site for
AT88SC0404CA-SH-T, AT88SC0808CA-SH, AT88SC0808CA-
SH-T, AT88SC0104CA-SH, AT88SC0104CA-SH-T,
AT88SC0204CA-SH, AT88SC0204CA-SH-T and
AT88SC0404CA-SH catalog part numbers (CPN) available in
8L SOIC (.150in) package.**

Purpose: Qualification of MTAI as an additional final test site for AT88SC0404CA-SH-T, AT88SC0808CA-SH, AT88SC0808CA-SH-T, AT88SC0104CA-SH, AT88SC0104CA-SH-T, AT88SC0204CA-SH, AT88SC0204CA-SH-T and AT88SC0404CA-SH catalog part numbers (CPN) available in 8L SOIC (.150in) package.

CCB No.: 7781

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria	Result
Bin and Yield Comparison	Test the same units at existing and destination locations and compare the Bin and Yield data.	3000	1	≤0.1%	Passed
Parametric Correlation	Characterize the same units at existing and destination locations and compare data	33	1	≤10.0%	Passed
Correlation Lot report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation.	33	1	≤0.1%	Passed